

## PATENT ABSTRACTS OF JAPAN



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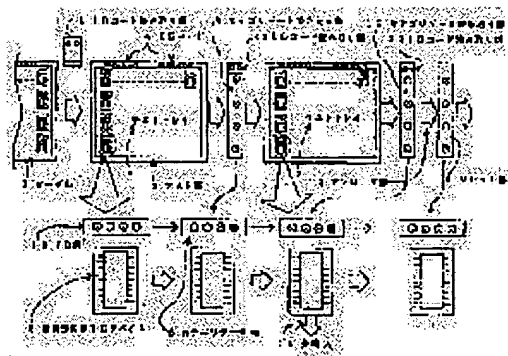
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## (54) TEST TRAY STRUCTURE FOR IC TEST HANDLER

## (57)Abstract:

PURPOSE: To accurately sort an IC device by category class based on the measured result by an IC tester.

CONSTITUTION: An ID code 4 is applied to a test tray 7, and a category data 6 is applied to an IC device 5 to be measured. A category data 6 section constituted of an ID board 13 capable of being written or erased based on the measured result by a test section 3 is provided on the periphery of each measured IC device 5 stored on the test tray 7 having the ID code 4. The category class judged data by the test section 3 is written on the ID board 13 of the category data 6 section. The category class judged data is read out from the test section 3 by an unloader section 10 via the ID code 4 of the test tray 7, and the measured IC device 5 is sorted by the category class only when the category class judged data, ID code 4, and the category data 6 section coincide.



## LEGAL STATUS

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